

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination MATSUSHITA ET AL.
	Examiner A. Sefer	Art Unit 2826

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0172039	11-2002	Inditsky, Ben-Zion	362/231
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	K	US-			
	L	US-			
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**NON-PATENT DOCUMENTS**

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